



Heterogeneous integration of chiplets Lego-like IP for more than Moore

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Gordon E. Moore Observations

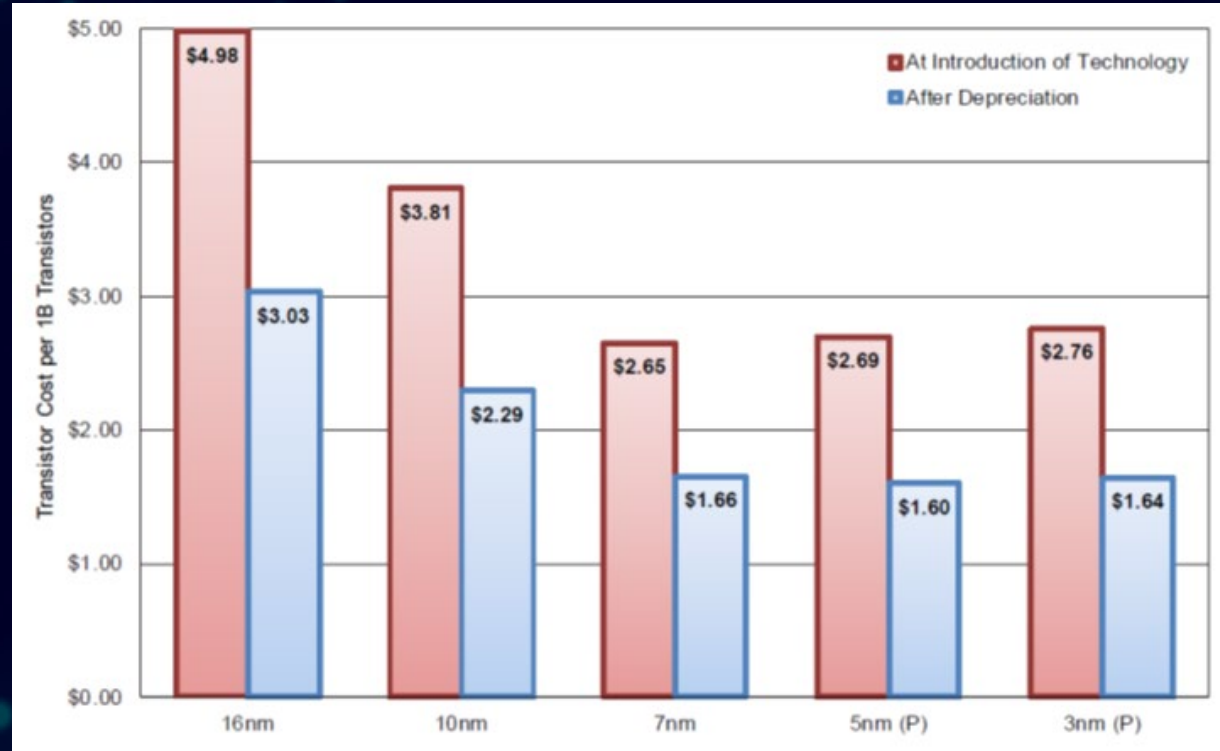
the number of transistors on a microchip doubles every two years, though the cost of computers is halved. This so called “Moore's Law” states that we can expect the speed and capability of our computers to increase every couple of years, and we will pay less for them. Another tenet of “Moore's Law” asserts that this growth is exponential

Expert opinions see these observations ending in the 2020's driven by:

1. Reticle limits
2. NRE costs
3. Availability of required IP
4. Yield
5. Die cost
6. Device scaling
7. Function aggregation
8. I/O scaling

Transistor Costs

Trends



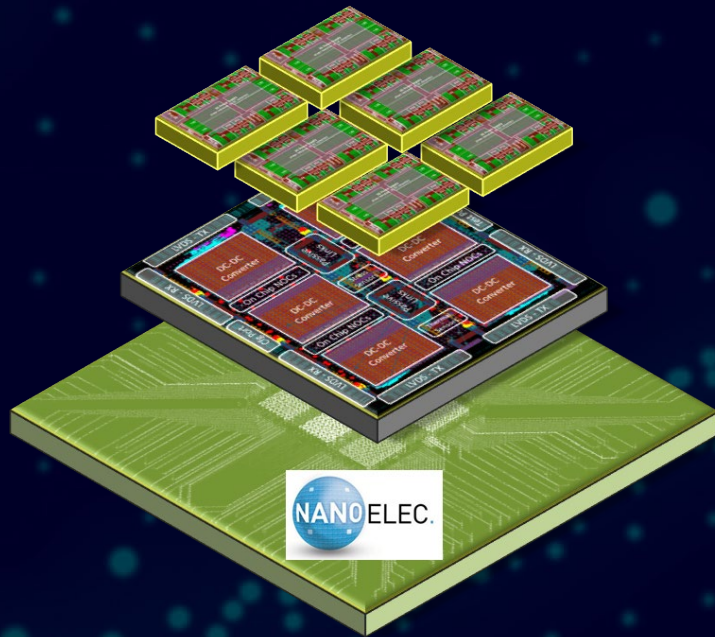
7nm the pivot point?

Monolithic forces all functions to be at same node

Memory and I/O not ideal

Technology inflection point

Trends



Cost and yield driving alternatives to monolithic solutions

- SOC disaggregation into hard IP or “chiplets”
- Multi-die implementation to avoid reticle limitations (vs. single die)

Data movement - low latency, high-bandwidth

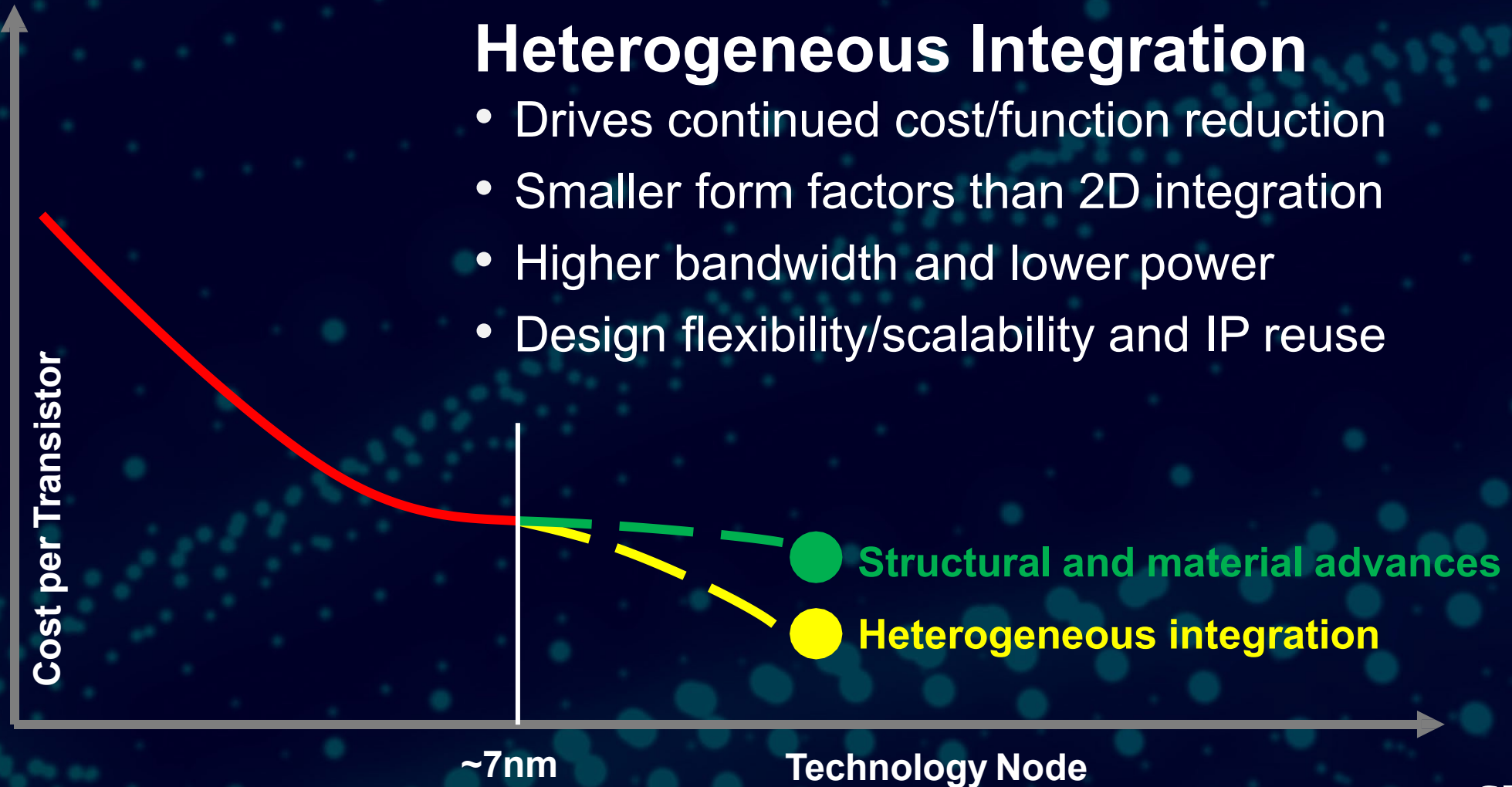
- Use of High Bandwidth Memory (HBM)
- 3D memory directly stacked on logic
- High-speed IO for chip-to-chip interfaces

Heterogeneous integration provides path forward

- Supports multiple micro-architecture scenarios
- Leveraging 2.5 and 3D assembly platforms
- Utilizes System Technology Co-optimization (STCO)

Extending “Moore’s Law”

Trends



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Heterogenous Integration path forward

Trends

Enabling alternative Micro-architectures

High Bandwidth Memory (HBM)

ASIC Die Disaggregation

ASIC IP Disaggregation

2.5D Silicon Interposers, Fanout/RDL, Silicon Bridge

3D IC Stacked Die

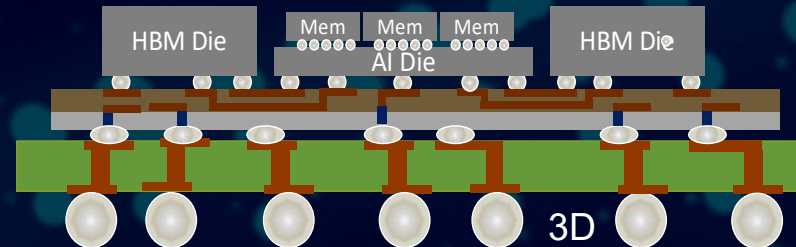
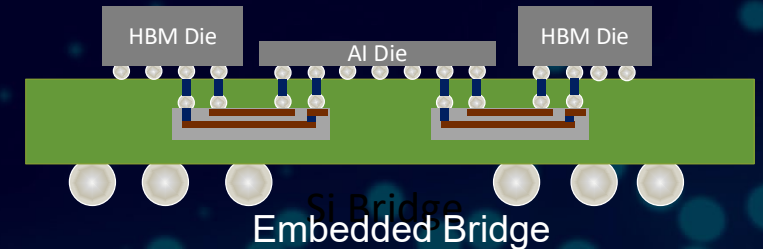
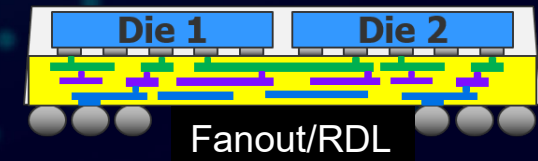
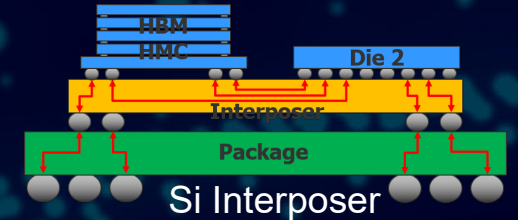
Key Benefits

Increased Performance

Reduced Power

Lower unit cost/NRE

Product Configurability

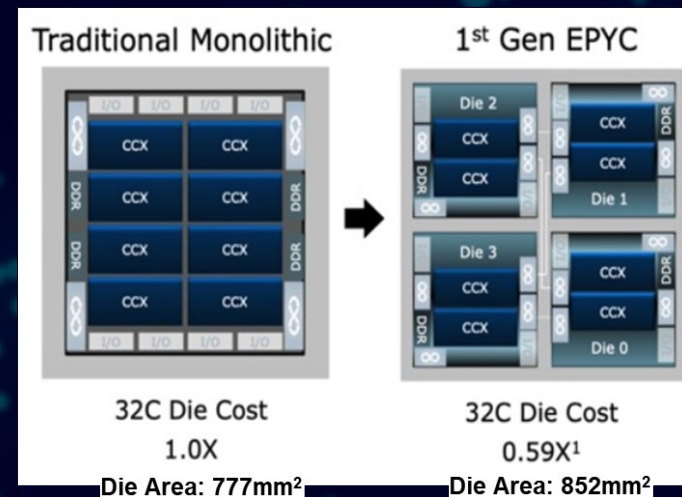


Case study results

Trends

AMD Cost comparison of chiplets vs. monolithic

- 41% reduction in die cost and higher yield
- Maximize platform value – product configurability from single tape-out



Presented at 2021 International Solid State Circuits Conference

Developing eco-system

- Standards for chiplet marketplace and exchange
- Turn-key design/build resources
- Materials suppliers

	Monolithic	Diff	Chiplet
Wafer Cost (7nm)	\$9,350	1x	\$9,350
Total Die Size	600mm ²	1.1x	660mm ²
Single Die Size	600mm ²		165mm ²
Gross Die per Wafer	96		387
Defect Rate (per cm ²)	0.2	1x	0.2
Effective Area	80%	1x	80%
Estimated Yield (Dingwall)	43%		78%
Net Die per Wafer	42		300
Single Die Cost	\$224		\$31
Total Die Cost	\$224		\$124
Total Test Cost	\$10	1.2x	\$12
Package and Packaging	\$160	1.25x	\$200
Packaging Loss	1%	4x	4%
Total Manufacturing Cost	\$398		\$347

Chipselets

Enabling modular function design

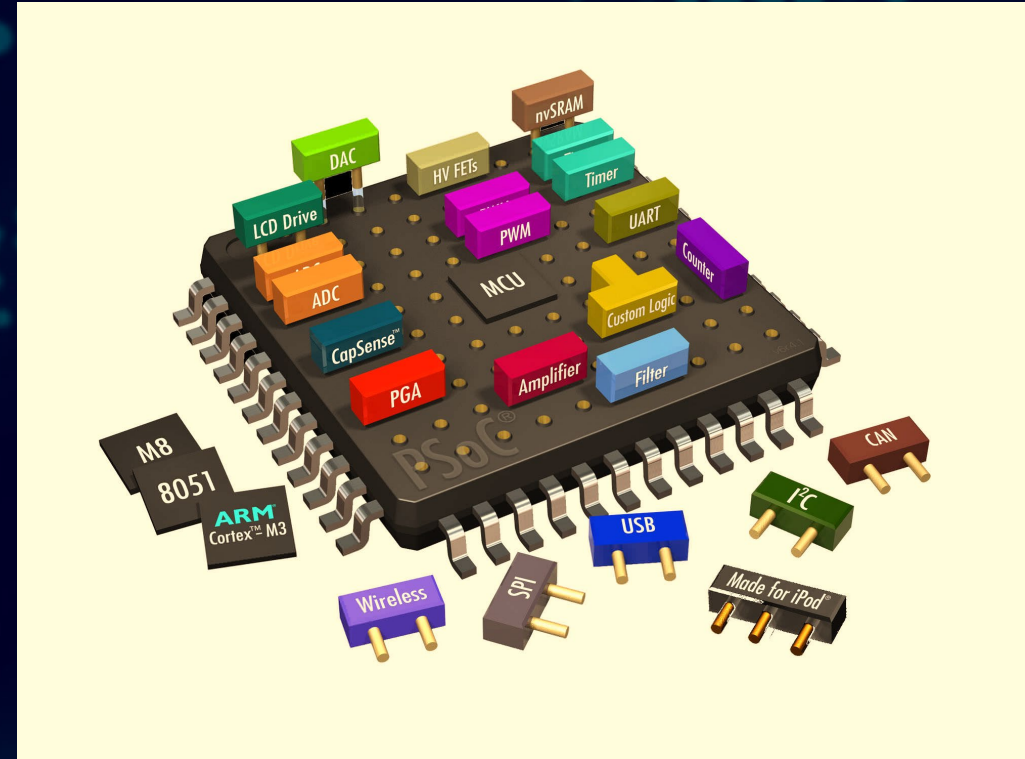
- No need to own/design full stack
- Aggregated with custom ASIC(s)

Fabricated using ideal nodes

Integrated through standardized interfaces and CDK's

Commercially available

Low NRE and fast TTM



Success with Chiplets

Needs

Chiplet design kits

Heterogeneous planning and co-optimization

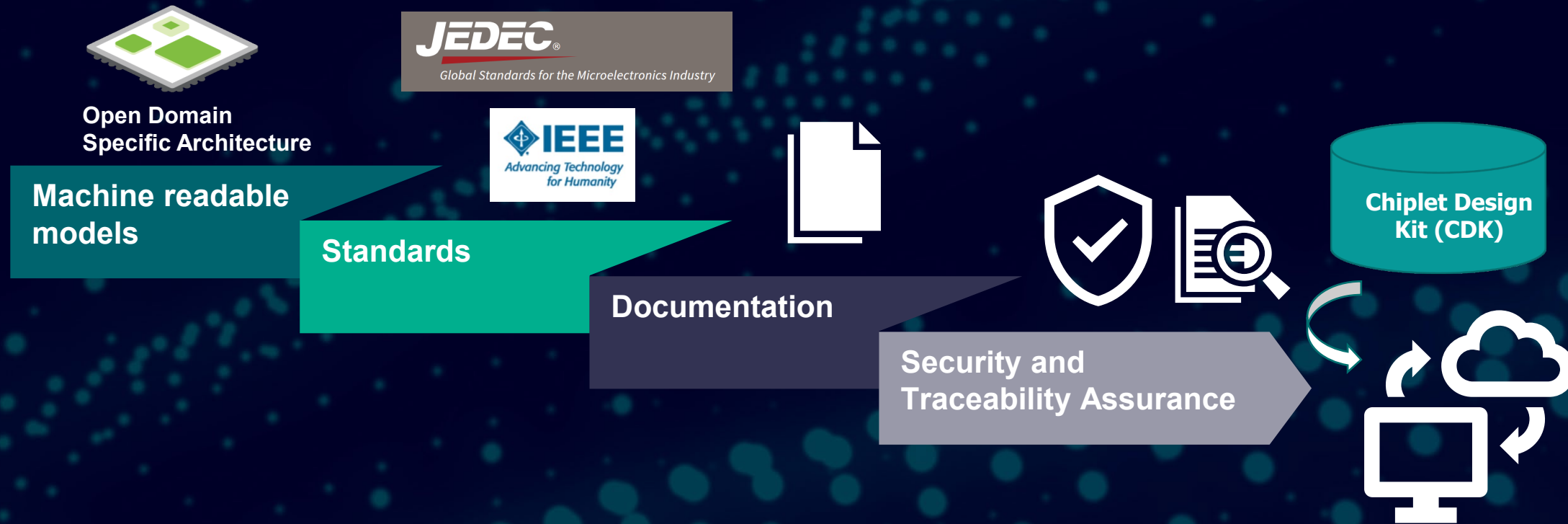
Physical verification at every level of 3D assembly

Multi-domain testing

Ecosystem interoperability

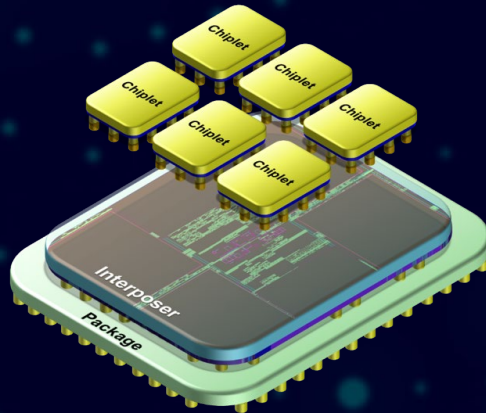
Standardized chiplet design kit

Needs

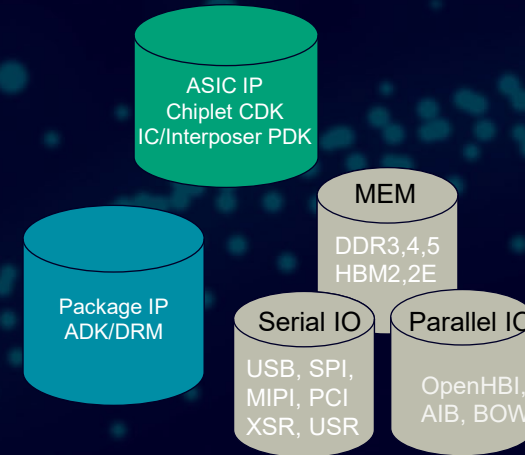


Chiplet ecosystem enablers

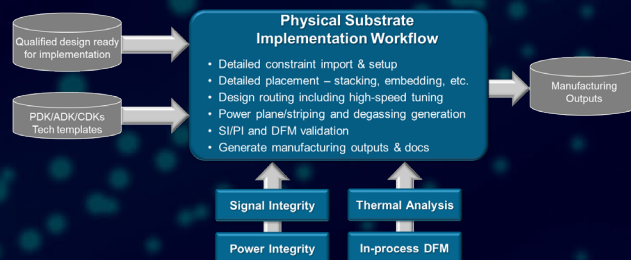
Needs



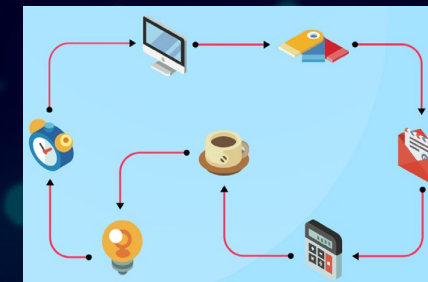
Technology



Intellectual property



Workflows/
design kits



Business models

Heterogeneous Planning & Prototyping

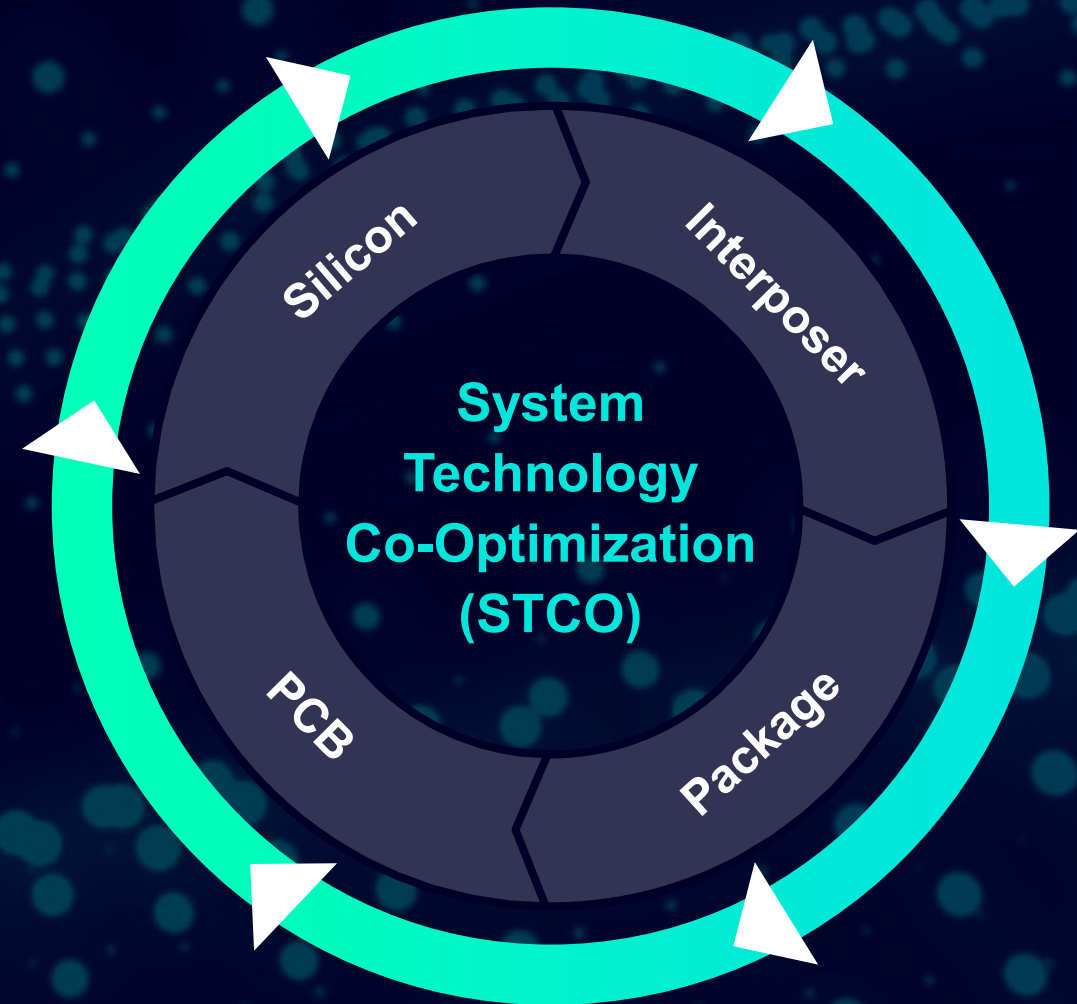
Needs

Single digital twin and system logi netlist

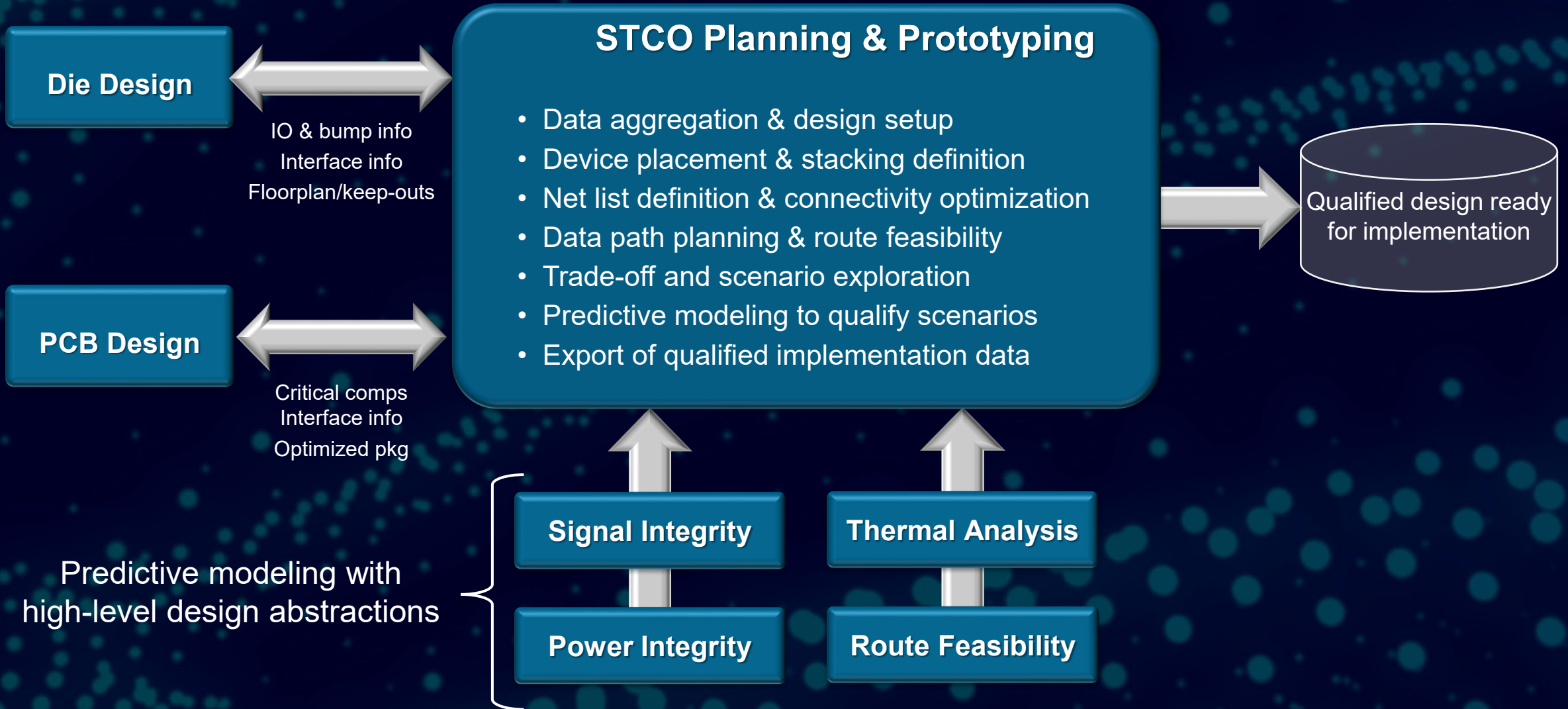
System Technology Co-Optimization

Predictive modeling to prototype and qualify design scenarios

Replacement of spreadsheet-based flows as communication mechanism of design intent



Planning and prototyping workflow



Verification at every level

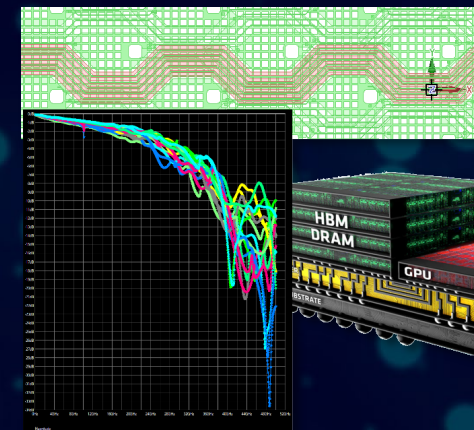
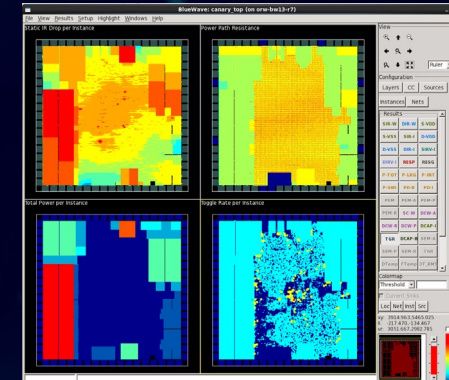
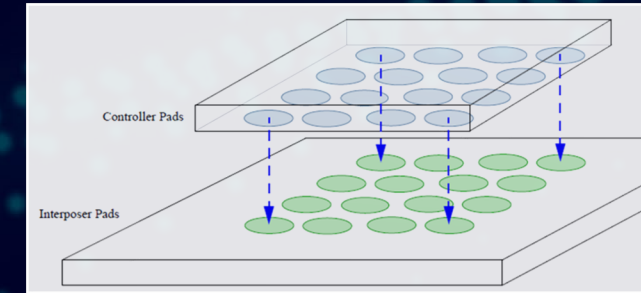
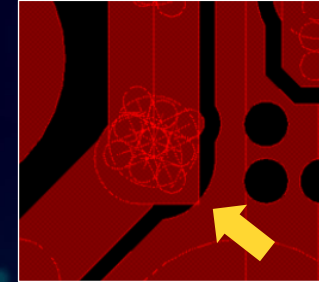
Needs

Substrate level fabrication DRC

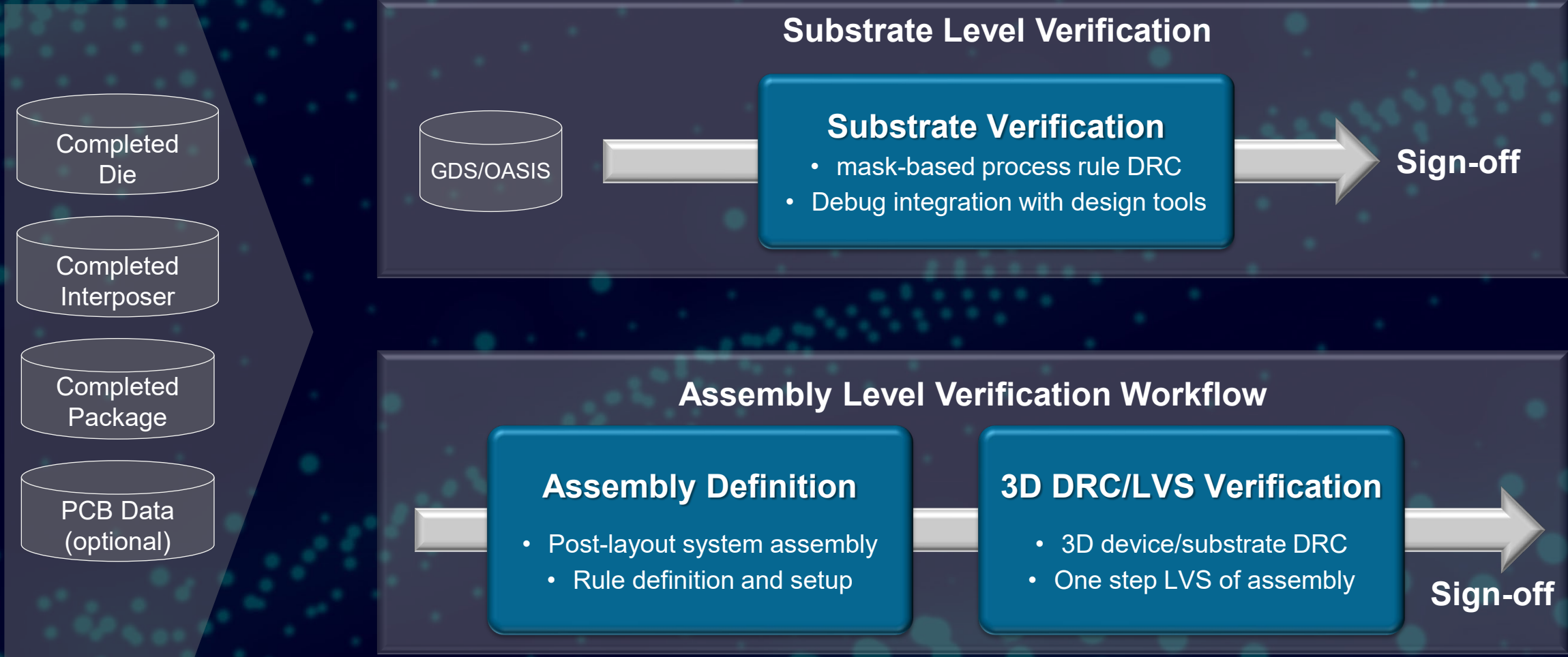
3D assembly level LVS

Predictive thermal, stress and reliability

Timing, signal and power integrity



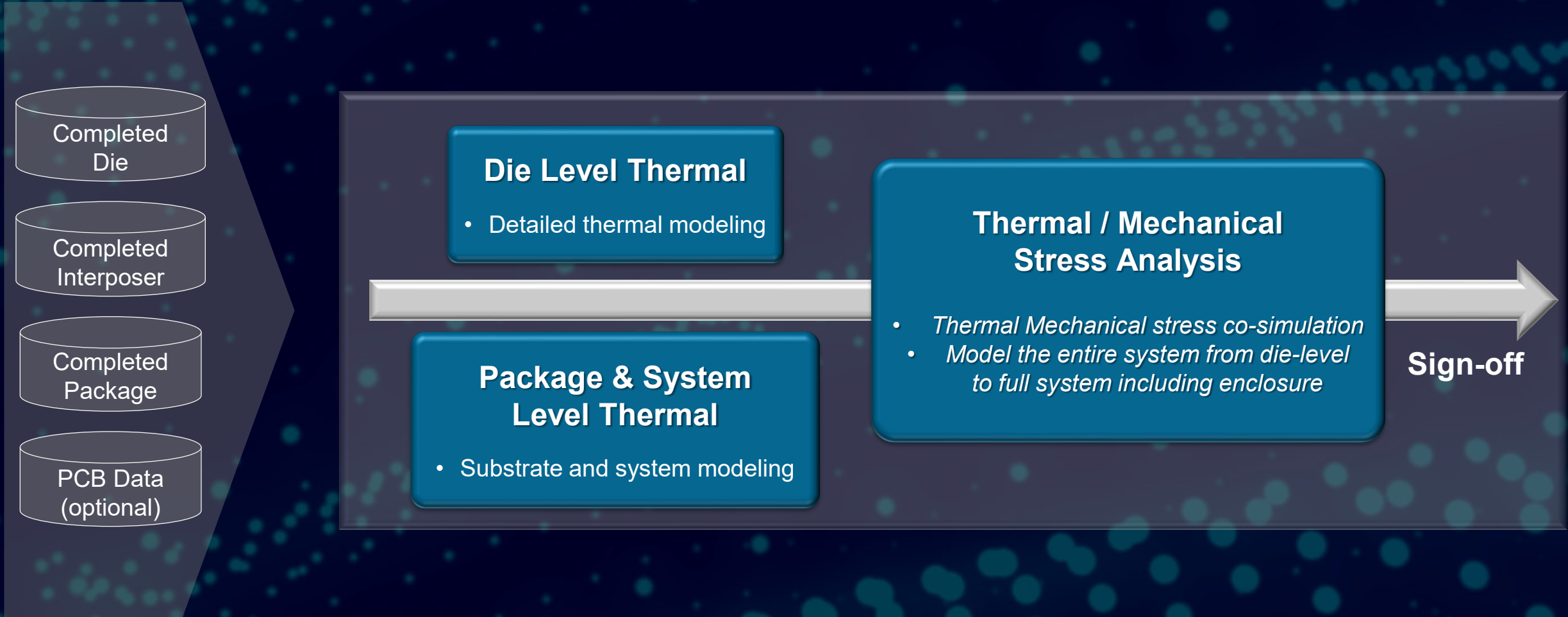
DRC/LVS verification workflows



SI/PI Modeling workflows



Thermal / stress workflow



DFT/Test

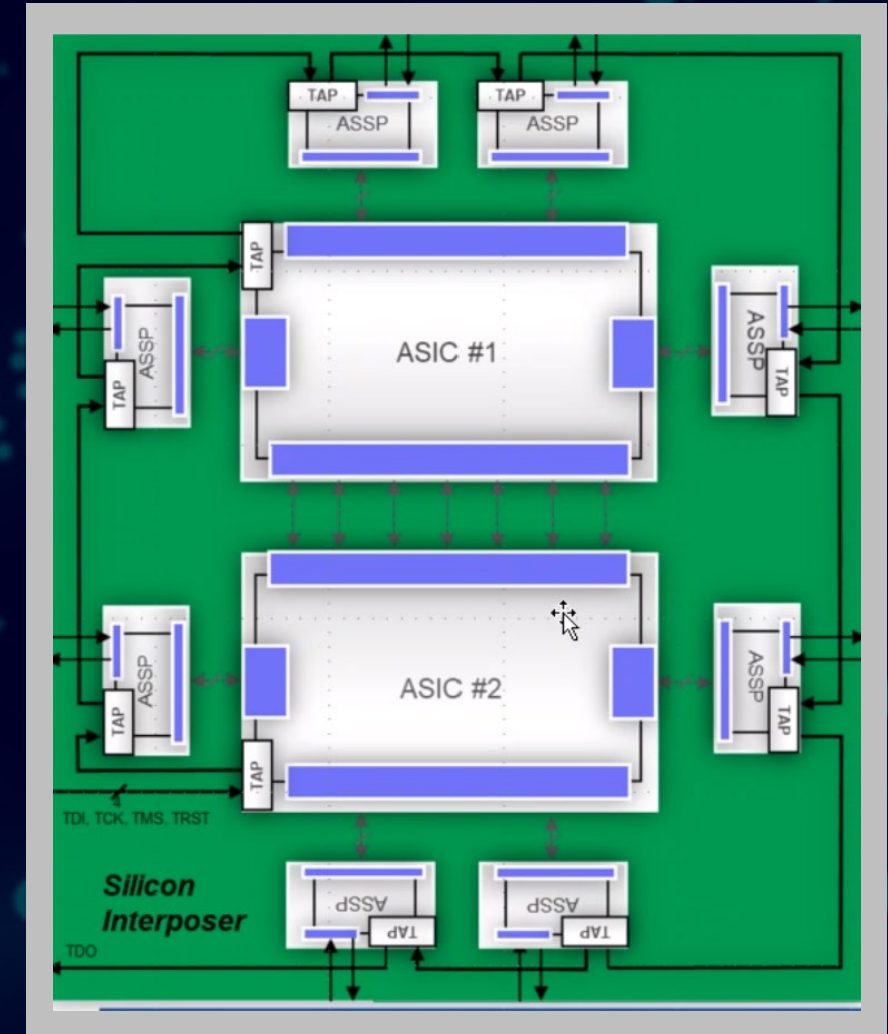
Needs

ASIC DFT Planning

Interposer DFT Planning

2.5/3D Level Testing

2.5/3D DFT Verification



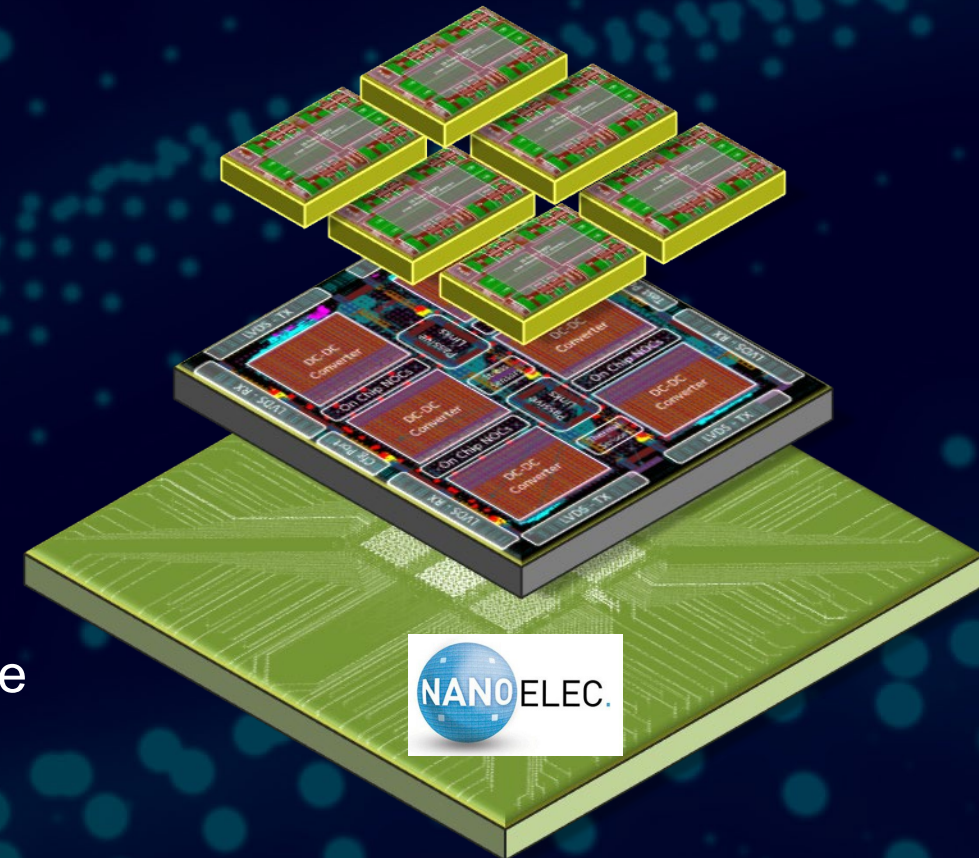
Summary

HI of chipelets using STCO enables compelling product benefits

- Increased Performance
- Reduced Power
- Lower unit cost/NRE
- Product configurability & hyper-scalability

General Comments & Observations

- Emerging chipelet Ecoystem
- Assess HI scenarios early in the product design cycle
- Advanced HI package/ASIC STCO Flow
 - Multi Domain Design Planning, Analysis & Signoff
 - Predictive multi-domain analysis



Design images courtesy of CEA-Leti

Thank You

